## **Power MOSFET**

## -60 V, -12 A, P-Channel DPAK

This Power MOSFET is designed to withstand high energy in the avalanche and commutation modes. Designed for low–voltage, high–speed switching applications in power supplies, converters, and power motor controls. These devices are particularly well suited for bridge circuits where diode speed and commutating safe operating areas are critical and offer an additional safety margin against unexpected voltage transients.

#### Features

- Avalanche Energy Specified
- I<sub>DSS</sub> and V<sub>DS(on)</sub> Specified at Elevated Temperature
- Designed for Low–Voltage, High–Speed Switching Applications and to Withstand High Energy in the Avalanche and Commutation Modes
- NVD and SVD Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

#### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Rating	Symbol	Value	Unit		
Drain-to-Source Voltage	V <sub>DSS</sub>	-60	Vdc		
Gate–to–Source Voltage – Continuous – Non–repetitive (t <sub>p</sub> ≤ 10 ms)	V <sub>GS</sub> V <sub>GSM</sub>	± 20 ± 25	Vdc Vpk		
Drain Current – Continuous @ T <sub>a</sub> = 25°C – Single Pulse (t <sub>p</sub> ≤ 10 ms)	I <sub>D</sub> I <sub>DM</sub>	-12 -18	Adc Apk		
Total Power Dissipation @ $T_a = 25^{\circ}C$	PD	55	W		
Operating and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	-55 to 175	°C		
$            Single Pulse Drain-to-Source Avalanche \\             Energy - Starting T_J = 25^\circ C \\              (V_{DD} = 25 Vdc, V_{GS} = 10 Vdc, Peak \\              I_L = 12 Apk, L = 3.0 mH, R_G = 25 \Omega )            $	E <sub>AS</sub>	216	mJ		
Thermal Resistance – Junction-to-Case – Junction-to-Ambient (Note 1) – Junction-to-Ambient (Note 2)	R <sub>θJC</sub> R <sub>θJA</sub> R <sub>θJA</sub>	2.73 71.4 100	°C/W		
Maximum Lead Temperature for Soldering Purposes, 1/8 in. from case for 10 seconds	ΤL	260	°C		

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

 When surface mounted to an FR4 board using 1 in pad size (Cu area = 1.127 in<sup>2</sup>).

 When surface mounted to an FR4 board using the minimum recommended pad size (Cu area = 0.412 in<sup>2</sup>).



### **ON Semiconductor®**

#### www.onsemi.com

V <sub>(BR)DSS</sub>	F	R <sub>DS(on)</sub> TYP	I <sub>D</sub> MAX
–60 V 155 mΩ @ –10 V, 6 A			–12 A
G O		P-Cr	annel
1 2 0 1 2 0 CASE STY	AK 369C	CAS	4 3 <b>PAK</b> SE 369D TYLE 2
		KING DIAGRAN NASSIGNMENT	
D	4 Irain		4 Drain
AY WW		purce 1	2 3 Drain Source
A NT2955/NV NT2955 Y WW G	2955	= Assembly Loca = Specific Device = Specific Device = Year = Work Week = Pb-Free Packa	e Code (DPAK) e Code (IPAK)
optional. In	cases	ocation code (A) is where the Assemb ckage, the front sid	bly Location is

#### ORDERING INFORMATION

code may be blank.

See detailed ordering and shipping information on page 5 of this data sheet.

#### **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = $25^{\circ}$ C unless otherwise noted)

Characteristic			Min	Тур	Max	Unit
OFF CHARACTERISTICS						
Drain-to-Source Breakdown Voltage (Note 3) ( $V_{GS} = 0 \text{ Vdc}, I_D = -0.25 \text{ mA}$ ) (Positive Temperature Coefficient)			-60 -	67		Vdc mV/°C
Zero Gate Voltage Drain Current ( $V_{GS} = 0$ Vdc, $V_{DS} = -60$ Vdc, T ( $V_{GS} = 0$ Vdc, $V_{DS} = -60$ Vdc, T		I <sub>DSS</sub>			-10 -100	μAdc
Gate-Body Leakage Current (VG	$_{\rm S}$ = ± 20 Vdc, V <sub>DS</sub> = 0 Vdc)	I <sub>GSS</sub>	-	-	-100	nAdc
ON CHARACTERISTICS (Note 3)						
Gate Threshold Voltage $(V_{DS} = V_{GS}, I_D = -250 \ \mu Adc)$ (Negative Temperature Coefficie	ent)	V <sub>GS(th)</sub>	-2.0	-2.8 4.5	-4.0 -	Vdc mV/°C
Static Drain–Source On–State Re $(V_{GS} = -10 \text{ Vdc}, I_D = -6.0 \text{ Adc})$	sistance	R <sub>DS(on)</sub>	_	0.155	0.180	Ω
$\label{eq:VGS} \begin{array}{l} \text{Drain-to-Source On-Voltage} \\ (\text{V}_{\text{GS}} = -10 \ \text{Vdc}, \ \text{I}_{\text{D}} = -12 \ \text{Adc}) \\ (\text{V}_{\text{GS}} = -10 \ \text{Vdc}, \ \text{I}_{\text{D}} = -6.0 \ \text{Adc}, \end{array}$	V <sub>DS(on)</sub>		-1.86 -	-2.6 -2.0	Vdc	
Forward Transconductance (V <sub>DS</sub>	gFS		8.0	-	Mhos	
DYNAMIC CHARACTERISTICS			1		1	
Input Capacitance		C <sub>iss</sub>	-	500	750	pF
Output Capacitance	$(V_{DS} = -25 \text{ Vdc}, V_{GS} = 0 \text{ Vdc}, F = 1.0 \text{ MHz})$	C <sub>oss</sub>	-	150	250	-
Reverse Transfer Capacitance		C <sub>rss</sub>	-	50	100	
SWITCHING CHARACTERISTICS	(Notes 3 and 4)					•
Turn-On Delay Time		t <sub>d(on)</sub>	-	10	20	ns
Rise Time	(V <sub>DD</sub> = -30 Vdc, I <sub>D</sub> = -12 A,	t <sub>r</sub>	-	45	85	
Turn–Off Delay Time	$V_{GS} = -10 \text{ V}, \text{ R}_{G} = 9.1 \Omega$	t <sub>d(off)</sub>	-	26	40	1
Fall Time		t <sub>f</sub>	-	48	90	
Gate Charge		QT	-	15	30	nC
	$(V_{DS} = -48 \text{ Vdc}, V_{GS} = -10 \text{ Vdc}, I_{D} = -12 \text{ A})$	Q <sub>GS</sub>	-	4.0	-	
	, , , , , , , , , , , , , , , , , , ,	$Q_{GD}$	-	7.0	-	
DRAIN-SOURCE DIODE CHARA	CTERISTICS (Note 3)					
Diode Forward On–Voltage ( $I_S = 12 \text{ Adc}, V_{GS} = 0 \text{ V}$ ) ( $I_S = 12 \text{ Adc}, V_{GS} = 0 \text{ V}, T_J = 150^{\circ}\text{C}$ )		V <sub>SD</sub>		-1.6 -1.3	-2.5 -	Vdc
Reverse Recovery Time (I <sub>S</sub> = 12 A, dI <sub>S</sub> /dt = 100 A/ $\mu$ s ,V <sub>GS</sub> = 0 V)		t <sub>rr</sub>	-	50		ns
		t <sub>a</sub>	-	40	-	1
		t <sub>b</sub>	-	10	-	1
Reverse Recovery Stored Charge		Q <sub>RR</sub>	-	0.10	-	μC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 3. Indicates Pulse Test: Pulse Width  $\leq$  300  $\mu$ s, Duty Cycle  $\leq$  2%. 4. Switching characteristics are independent of operating junction temperature.

#### TYPICAL PERFORMANCE CURVES (T<sub>J</sub> = 25°C unless otherwise noted)







Figure 11. Maximum Rated Forward Biased Safe Operating Area

Figure 12. Diode Reverse Recovery Waveform



Figure 13. Thermal Response

#### ORDERING INFORMATION

Device	Package	Shipping <sup>†</sup>
NTD2955G	DPAK (Pb–Free)	75 Units / Rail
NTD2955–1G	IPAK (Pb–Free)	75 Units / Rail
NTD2955T4G	DPAK (Pb–Free)	2500 / Tape & Reel
NVD2955T4G*	DPAK (Pb–Free)	2500 / Tape & Reel
SVD2955T4G*	DPAK (Pb–Free)	2500 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

\*NVD and SVD Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC–Q101 Qualified and PPAP Capable.

#### PACKAGE DIMENSIONS

#### **DPAK (SINGLE GAUGE)** CASE 369C

**ISSUE F** 





\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

- NOTES: 1. DIMENSIONING AND TOLERANCING PER ASME
- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
  CONTROLLING DIMENSION: INCHES.
  THERMAL PAD CONTOUR OPTIONAL WITHIN DI-MENSIONS 53, L3 and Z.
  DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE.
  DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
  DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.
- PLANE H.

7. OP	TIONAL	MOLD	FEATURE	

	INCHES		INCHES MILLIMETE		IETERS
DIM	MIN	MAX	MIN	MAX	
Α	0.086	0.094	2.18	2.38	
A1	0.000	0.005	0.00	0.13	
b	0.025	0.035	0.63	0.89	
b2	0.028	0.045	0.72	1.14	
b3	0.180	0.215	4.57	5.46	
С	0.018	0.024	0.46	0.61	
c2	0.018	0.024	0.46	0.61	
D	0.235	0.245	5.97	6.22	
Е	0.250	0.265	6.35	6.73	
е	0.090	BSC	2.29	BSC	
Н	0.370	0.410	9.40	10.41	
L	0.055	0.070	1.40	1.78	
L1	0.114	REF	2.90	REF	
L2	0.020	BSC	0.51	BSC	
L3	0.035	0.050	0.89	1.27	
L4		0.040		1.01	
Z	0.155		3.93		

STYLE 2: PIN 1. GATE 2. DRAIN 3. SOURCE 4. DRAIN

#### PACKAGE DIMENSIONS



IPAK CASE 369D ISSUE C

NOTES:

z

1. DIMENSIONING AND TOLERANCING PER

ANSI Y14.5M, 1982. 2. CONTROLLING DIMENSION: INCH.

	INCHES		MILLIN	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.235	0.245	5.97	6.35
В	0.250	0.265	6.35	6.73
С	0.086	0.094	2.19	2.38
D	0.027	0.035	0.69	0.88
Е	0.018	0.023	0.46	0.58
F	0.037	0.045	0.94	1.14
G	0.090 BSC		2.29 BSC	
н	0.034	0.040	0.87	1.01
J	0.018	0.023	0.46	0.58
κ	0.350	0.380	8.89	9.65
R	0.180	0.215	4.45	5.45
S	0.025	0.040	0.63	1.01
V	0.035	0.050	0.89	1.27
Ζ	0.155		3.93	

STYLE 2: PIN 1. GATE 2. DRAIN 3. SOURCE

4. DRAIN

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